

ANSI/EIA-469-E-2017 Approved: April 25, 2017

EIA STANDARD

EIA-469-E

Standard Test Method for Destructive Physical Analysis (DPA) of Ceramic Monolithic Capacitors

EIA-469-E (Revision of EIA-469-D)

April 2017



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(From Standards Proposal No. 5217, formulated under the cognizance of the P-2.1 Committee on EIA National Ceramic and Dielectric Capacitors Standards).

Published by

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Foreword

This Standard was prepared under the cognizance of the P-2.1 Engineering Subcommittee on Ceramic Dielectric Capacitors of the Electronic Components Industry Association.